

Search Notes

Application/Control No.

10/817,553

Examiner

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Applicant(s)/Patent under
Reexamination

REED, DAVID G.

Art Unit

2181

SEARCHED

Class	Subclass	Date	Examiner
710	5-6, 22-35, 52-57, 309-312	12/23/2006	CS
711	112-113	12/23/2006	CS
711	142-143	12/23/2006	CS
711	149-159	12/23/2006	CS
711	169	12/23/2006	CS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
710	310,311,5	12/24/2006	CS
710	23,33,52	12/24/2006	CS
711	141,154	12/24/2006	CS
711/169		12/24/2006	CS

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS	6/8/2006	CS
PALM	6/8/2006	CS
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWNET, IBMTDB)	12/23/2006	CS